# MSKSEMI 美森科













**ESD** 

/S

TSS

MOV

GDI

 $\mathsf{PLED}$ 

5P06-MS

**Product specification** 





#### **Description**

The 5P06-MS is the high cell density trenched P-ch MOSFETs, which provides excellent RDSON and efficiency for most of the small power switching and load switch applications.

The 5P06-MS meet the RoHS and Green Productrequirement with full function reliability approved.

## **Product Summary**

BVDSS	-60V
RDSON	110mΩ
ID	-5A

#### **FEATURE**

- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

#### **Reference News**

PACKAGE OUTLINE	PIN CONFIGURATION	Marking
	D O S	MSKSEMI 5P06 MS
SOT-223		

**Absolute Maximum Ratings** (T<sub>A</sub>=25 ℃ unless otherwise noted)

Parameter	Symbol	Value	Unit	
Drain-Source voltage	<b>V</b> DS	-60	V	
Gate-Source voltage	<b>V</b> GS	±20	_ v	
Continuous Drain Current	ľο	-5.0	Α	
Pulsed Drain Current <sup>1</sup>	Ірм	-5.2	А	
Power Dissipation	P <sub>D</sub>	1	W	
Junction Temperature	TJ	150	°C	
Storage Temperature	Тѕтс	-55~ 150	°C	
Thermal Resistance from Junction to Ambient <sup>2</sup>	Rеja	125	°C/W	



# Electrical Characteristics (T =25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Тур	Max	Unit
Static Elec	trical Characteristics @ TJ = 25°C (unless	otherwise stated)				
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V <sub>G</sub> s=0V I <sub>D</sub> =-250μA	-60			V
	Zero Gate Voltage Drain Current(T₄=25℃)	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V			-1	μА
DSS	Zero Gate Voltage Drain Current(T₄=125℃)	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V			-100	uA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>G</sub> s=±20V, V <sub>D</sub> s=0V			±100	nA
$V_{\rm GS(TH)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250µA	-1.0	-1.5	-2.5	V
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance②	V <sub>G</sub> s=-10V, I <sub>D</sub> =-2A		110	180	mΩ
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance②	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-1A		150	200	mΩ
Dynamic E	Electrical Characteristics @ TJ = 25°C (unl	ess otherwise stated)		<u> </u>	ı	<u> </u>
C <sub>iss</sub>	Input Capacitance			310		pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V, f=1MHz		22		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			15		pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =-30V		5.4		nC
$Q_{gs}$	Gate Source Charge	lp=-2A,		1.1		nC
$Q_{gd}$	Gate Drain Charge	Vgs=-10V		1.6		nC
	Characteristics		·	•		
t <sub>d(on)</sub>	Turn on Delay Time			41		ns
t <sub>r</sub>	Turn on Rise Time	V <sub>DD</sub> =-30V, l <sub>D</sub> =-2A, R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =-10V		22		ns
$t_{d(off)}$	Turn Off Delay Time		-	25		ns
t <sub>f</sub>	Turn Off Fall Time			32		ns
Source Dra	ain Diode Characteristics					
l <sub>SD</sub>	Source drain current(Body Diode)	Ta=25℃			-2.0	А
$V_{\text{SD}}$	Forward on voltage②	Tj=25℃, Isp=-2A, Vgs=0V		-0.84	-1.2	V



#### **Typical Characteristics**

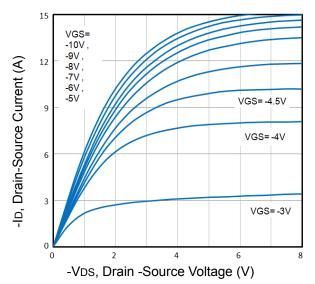


Fig1. Typical Output Characteristics

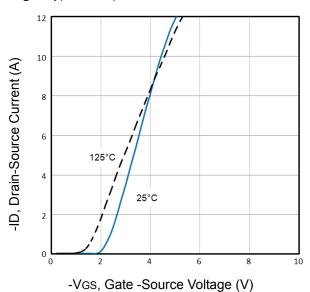


Fig3. Typical Transfer Characteristics

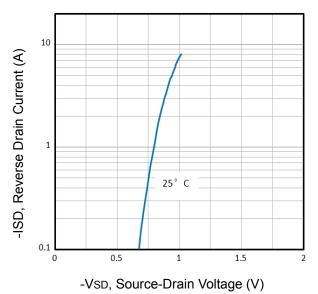


Fig5. Typical Source-Drain Diode Forward Voltage

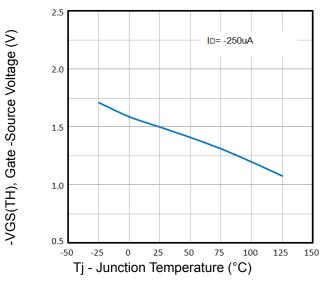


Fig2. Normalized Threshold Voltage Vs. Temperature

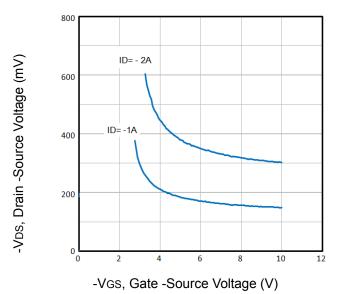
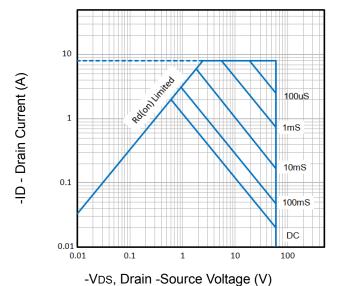


Fig4. Drain -Source Voltage vs Gate -Source Voltage





## **Typical Characteristics**

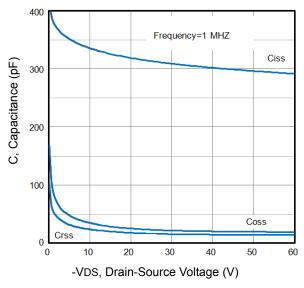


Fig7. Typical Capacitance Vs. Drain-Source Voltage

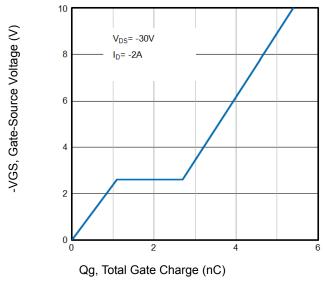


Fig8. Typical Gate Charge Vs. Gate-Source Voltage

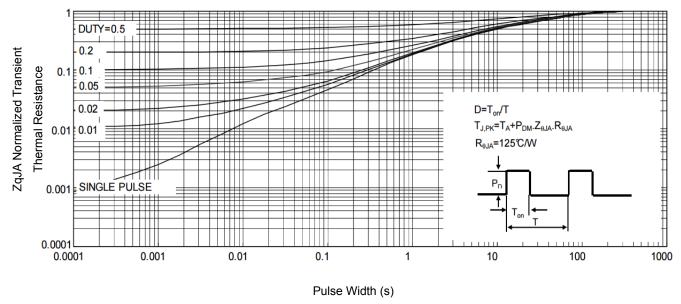


Fig9. Normalized Maximum Transient Thermal Impedance

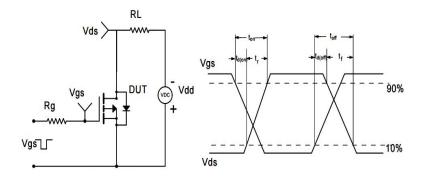
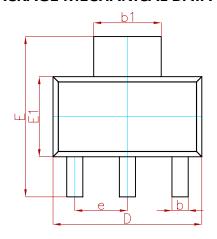
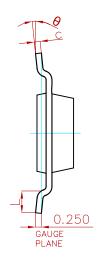


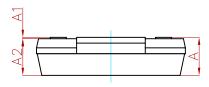
Fig10. Switching Time Test Circuit and waveforms



## PACKAGE MECHANICAL DATA

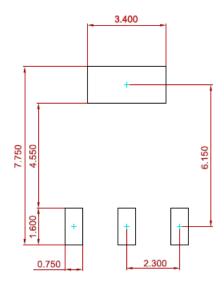






Symbol	Dimensions In Millimeters		Dimensions In Inches	
Cyllibol	Min.	Max.	Min.	Max.
Α		1.800		0.071
A1	0.020	0.100	0.001	0.004
A2	1.500	1.700	0.059	0.067
b	0.660	0.840	0.026	0.033
b1	2.900	3.100	0.114	0.122
С	0.230	0.350	0.009	0.014
D	6.300	6.700	0.248	0.264
E	6.700	7.300	0.264	0.287
E1	3.300	3.700	0.130	0.146
е	2.300(	BSC)	0.091	BSC)
L	0.750		0.030	
θ	0°	10°	0°	10°

### **Suggested Pad Layout**



#### Note:

- 1. Controlling dimension: in millimeters.
- 2.General tolerance:±0.050mm.
- 3. The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
5P06-MS	SOT-223	1000



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